

2-Isopropyl-4-methyl-4-phenyl-1,2,3,4-tetrahydroisoquinoline-1-thione

Hiroyuki Hosomi,^a Shigeru Ohba^{a*} and Hiromu Aoyama^b

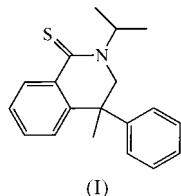
^aDepartment of Chemistry, Faculty of Science and Technology, Keio University, Hiyoshi 3-14-1, Kohoku-ku, Yokohama 223-8522, Japan, and ^bDepartment of Material Chemistry, Faculty of Textile Science and Technology, Shinshu University, Tokida 3-15-1, Ueda 386-0081, Japan
Correspondence e-mail: ohba@chem.keio.ac.jp

Received 3 March 2000

Accepted 13 March 2000

Data validation number: IUC0000079

The title compound, C₁₉H₂₁NS, is the photoproduct obtained from *N*-isopropyl-*N*-[(*E*)-2-phenylpropenyl]thiobenzamide. Recrystallization showed a spontaneous resolution.



Experimental

The title compound was prepared by one of the authors (HA) in a study on photocyclization of enamides and thioamides in the solid state (Aoyama, 2000). Crystals were grown from a hexane solution.

Crystal data

C₁₉H₂₁NS
M_r = 295.44
Orthorhombic, *P*2₁2₁2₁
a = 11.166 (1) Å
b = 13.423 (1) Å
c = 10.878 (1) Å
V = 1630.4 (2) Å³
Z = 4
D_x = 1.204 Mg m⁻³

Mo *K*α radiation
Cell parameters from 25 reflections
θ = 14.0–14.8°
μ = 0.192 mm⁻¹
T = 298 (1) K
Prism, yellow
0.55 × 0.40 × 0.30 mm

Data collection

Rigaku AFC-7R diffractometer
θ-2*θ* scans
Absorption correction: by integration (Coppens *et al.*, 1965)
*T*_{min} = 0.928, *T*_{max} = 0.947
3090 measured reflections
2684 independent reflections
1963 reflections with *I* > 2σ(*I*)

*R*_{int} = 0.006
*θ*_{max} = 30.0°
h = 0 → 16
k = -10 → 19
l = -8 → 16
3 standard reflections every 150 reflections
intensity decay: none

Refinement

Refinement on *F*²
R(*F*) = 0.043
wR(*F*²) = 0.124
S = 1.06
2684 reflections
190 parameters
H-atom parameters not refined

w = 1/[σ²(*F_o*²) + (0.0601*P*)² + 0.1846*P*]
where *P* = (*F_o*² + 2*F_c*²)/3
(Δ/σ)_{max} = 0.001
Δρ_{max} = 0.15 e Å⁻³
Δρ_{min} = -0.27 e Å⁻³
Absolute structure: Flack (1983), no Friedel pairs
Flack parameter = 0.1 (1)

Table 1

Selected geometric parameters (Å).

S1—C3	1.681 (2)	C9—C14	1.510 (3)
N2—C3	1.326 (3)	C13—C14	1.533 (4)
N2—C13	1.470 (3)		

X-ray intensity data were measured for *h*,*k*,*l* (*θ* < 30°) and for *h*,*-k*,*-l* (*θ* < 15°). The chiral space group and Flack parameter of 0.1 (1) suggested a spontaneous resolution of the title compound. All H-atom positional parameters were calculated geometrically and fixed with *U*_{iso}(H) = 1.2*U*_{eq}(parent atom).

Data collection: *MSC/AFC Diffractometer Control Software* (Molecular Structure Corporation, 1993); cell refinement: *MSC/AFC Diffractometer Control Software*; data reduction: *TEXSAN* (Molecular Structure Corporation, 1999); program(s) used to solve structure: *SIR92* (Altomare *et al.*, 1994); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); software used to prepare material for publication: *TEXSAN*.

References

- Altomare, A., Cascarano, G., Giacovazzo, C., Guagliardi, A., Burla, M. C., Polidori, G. & Camalli, M. (1994). *J. Appl. Cryst.* **27**, 435.
Aoyama, H. (2000). To be published.
Coppens, P., Leiserowitz, L. & Rabinovich, D. (1965). *Acta Cryst.* **18**, 1035–1038.
Flack, H. D. (1983). *Acta Cryst.* **A39**, 876–881.
Molecular Structure Corporation (1993). *MSC/AFC Diffractometer Control Software*. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
Molecular Structure Corporation (1999). *TEXSAN*. Version 1.10. MSC, 3200 Research Forest Drive, The Woodlands, TX 77381, USA.
Sheldrick, G. M. (1997). *SHELXL97*. University of Göttingen, Germany.